

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/636,128	HATHAWAY, THOMAS W.	
Examiner		Art Unit		Page 1 of 3
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Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
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	Steven B. Theriault	2179	

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	Examiner	Art Unit	Page 3 of 3
Steven B. Theriault	2179		

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